

The University of Arizona

Engineering College

Department of Electrical Engineering

Computer Science Research Laboratory

CSRL Memo No. 199

LOCUTI: A TEST PROGRAM

FOR THE PDP-9/LOCUST HYBRID INTERFACE

January, 1970

by W. R. Moore



ACKNOWLEDGEMENT:

The writer is grateful to the National Aeronautics and Space Administration for their support of this work under NASA Grant ~~NAG-644~~. NGL-03-002-024

FACILITY FORM 602

N 70-27171		(ACCESSION NUMBER)	(THRU)
22		/	/
CR-109843		(PAGES)	(CODE)
		08	(CATEGORY)
(NASA CR OR TMX OR AD NUMBER)			

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INTRODUCTION

LOCUT1 is a Fortran 4V main program which calls Macro-9 subroutines to test the Computer Science Research Laboratory's hybrid computer interface between the PDP-9 digital computer and the LOCUST high speed iterative analog computer. The programs are written to provide the user with all the information he needs to perform the tests, assuming of course a reasonable familiarity with both of the computers and the interface itself. The programs ask questions, give patching and test operating instructions, and print out diagnostic messages on the teletype to point out any malfunction in the interface.

In writing the programs, priority was given to user convenience, not to programming efficiency. Because of this and the secondary purpose of the project, to familiarize the writer with PDP-9 programming, a variety of things were done "the hard way."

LOCUT1 in its present form performs four basic tests of the interface by calling four subroutines: the free flag/IOT test by calling FFIOT; the control register/read-in gate test by calling CONREG; the pre-set counters by calling PRECTR; and the MDAC/ADC test by calling CONV.

FREE FLAG/IOT TEST

FFIOT is the subroutine called by LOCUT1 to test the free flags and patchable IOT's that appear on the LOCUST digital patchbay. As in all of the interface tests, one interface component must be used to test another; here, the IOT's are issued by the PDP-9 and then used to set the free flags. Since the free flags remain set only while there is a logical "1" input to them, the IOT's are run through ~~in~~ a toggled J-K flip flop to set the flags. This means that after a flag has been checked with a skip instruction, it must be cleared by issuing the IOT again to toggle the flip flop to a "0." Care must also be taken to insure that the flip flop is initially reset to a "0" output when the test begins. This is best done by using one of the logic state indicator lamps and a push button connected to the reset input of the flip flop.

FFIOT initializes six locations to contain one. If one of the flags fails to set when one of the IOT's is issued, one of these six locations is set to zero. If the test is successful, the location is not changed. When control returns to LOCUT1, these locations are converted to logical variables and tested to determine which diagnostic messages to print out. These logical tests are necessary since a negative result from one free flag/IOT pair is not sufficient for a conclusion; it must be compared with a positive result which includes one of the pair.

CONTROL REGISTER/READ-IN GATE TEST

The 6-bit control register is tested in conjunction with the the 6-bit read-in gates. The control register outputs are patched to the read-in gate inputs bit for bit and to six logic state indicator lamps which are used as a visual check in case the read-in gates fail. This visual check requires some effort on the part of the user, but much less effort than would be involved in patching a logic scheme that would avoid it. LOCUT1 calls CONREG which first transfers all ones then all zeros to the control register and checks the result fed back by the read-in gates. If any bits fail, a macro is called which determines the error bits and instructs the user in further tests. If the control register is at fault, one of patchable IOT's must be used to check the read-in gates. CONREG uses Macro-9 input-output statements to provide the user with documentation of the test results.

Note that the user must be sure that the read-in gates are properly patched to accumulator bits 0-5 in the data channel patchbay, and that the read request pulse is provided there.

PRE-SET COUNTER TEST

The pre-set counters are checked with PRECTR and ERROR, a Fortran subroutine called by PRECTR. The decimal number 600 is loaded into each counter and then IOT's are counted

until 600 of them have been issued or until the counter "s" output goes through its positive logical transition. If the counter fails to set after 600 pulses, the program informs the user that that is the case. If the counter sets before 600 pulses have been issued, PRECTR calls ERROR which prints out the number which the counter did count before it set.

In this test toggled J-K flip flops are also used and care must be used in insuring that they are initially reset.

MDAC/ADC TEST

The MDAC/ADC test differs from the other three in that the user is not only interested in whether the components work, but in how accurate they are. Therefore the program allows a great deal of flexibility. The user selects any MDAC/ADC pair and patches them as instructed. A digital quantity is set in the accumulator switches 0-10 and read into the MDAC by CONV. By patching the MDAC output to an ADC input, and to a digital voltmeter, both the MDAC and ADC accuracy can be checked: the MDAC by comparing the accumulator switches with the DVM reading, and the ADC by comparing the DVM reading with the quantity remaining in the accumulator switches when the program halts. To check another quantity, the new value is set in the accumulator and the "CONTINUE" switch on the PDP-9 keyboard is depressed. To check another MDAC/ADC pair, octal 000001 is set in the

accumulator switches and the "CONTINUE" switch again depressed. The program then asks for the number of the MDAC and the ADC and proceeds as before. To terminate the test, enter zero for the MDAC number.

OPERATING NOTES

The program allows the user to request patching instructions, or ~~to~~ have them suppressed. Any tests the user does not wish to run may also be suppressed. However, unless the user is certain that the control register and the free flags and IOT's are properly operating, they should be tested before running the pre-set counter test or the MDAC/ADC test. PRECTR uses the free flags and IOT's, and CONV uses the control register.

If all tests are to be run, digital patchbay economy can be achieved by patching the free flag/IOT test and the control register/ read-in gate test on the same patchbay, and the pre-set counter and MDAC/ADC test on the same patchbay. Analog patching is required only for the converter tests, and this is the only time LOCUST must be in any mode other than patch.

CONCLUSION

It is felt that programs of this type will be a great help in using and maintaining the PDP-9 LOCUST interface.

LOCUT1 can easily be expanded to test other interface functions as they are added, e.g. the data channel. As the system now stands, the only function not exercised by LOCUT1 is the program interrupt facility. Future versions of the program will be named LOCUT2, LOCUT3, etc.

The programs are written to be self-explanatory, but the user must be thoroughly familiar with LOCUST, the PDP-9 and the interface. The programs themselves and two sample test print outs are included at the end of this paper. The first print out includes all patching instructions and tests and indicates a properly working interface. The second one is an example of the diagnostics output when there are malfunctions.

REFERENCES

1. Conant, Brian K., Design of a New Solid State Electronic Differential Analyzer Making Use of Integrated Circuits, Ph. D. Dissertation, University of Arizona, 1968.
2. Goltz, John R., An Economical Analog-to-Digital Converter System for Hybrid Computers, ACL Memo No. 147.
3. Wilkins, Jeff, A Modern Hybrid Computer Interface, Masters Thesis, University of Arizona, 1969.

MONITOR VAB

5LOAD

LOADER V5A

>LOCUTI, FFIOT, CONREG, PRECTR, ERROR, CONV

LOCUTI 33690

FFIOT 33512

CONREG 31167

PRECTR 30723

ERROR 30645

CONV 30473

.DA 30424

BCD103 25263

.SS 25204

FICPS 24456

OTSER 24354

INTEGE 24236

REAL 23233

1S1Q1

MONITOR VAB

SG 1

1S

"LOCUTI"

PDP-9/LOCUST HYBRID INTERFACE TEST!

DO YOU WISH PATCHING INSTRUCTIONS?

YES

TYPE "NO" AFTER TESTS NOT TO BE RUN.

FREE FLAG/IOT TEST?

YES

CONTROL REGISTER/READ-IN GATE TEST?

YES

PRE-SET COUNTER TEST?

YES

MDAC/ADC TEST?

YES

FREE-FLAG/IOT TEST:

PATCH EACH "PATCHABLE" IOT TO A 3-INPUT "OR" GATE AND THE GATE OUTPUT TO J&K INPUTS OF A FLIP FLOP. THEN PATCH THE FLIP FLOP OUTPUT TO BOTH FREE FLAGS. (NOTE THAT THE FLIP FLOP IS TOGGLED AND MUST BE RESET BEFORE STARTING THE TEST.)

TYPE "GO" WHEN PATCHING COMPLETE.

GO

FREE FLAG 0 OKAY

FREE FLAG 1 OKAY

IOT1 OKAY

IOT2 OKAY

IOT4 OKAY

FREE-FLAG/IOT TEST COMPLETE!

CONTROL REGISTER/READ-IN GATE TEST:

PATCH CONTROL REGISTER OUTPUTS TO CORRESPONDING READ-IN GATE INPUTS AND TO 6 LOGIC-STATE INDICATOR LAMPS. THE LAMPS ARE USED AS A VISUAL CHECK IN CASE THE READ-IN GATES FAIL.

TYPE "GO" WHEN PATCHING COMPLETE.

GO

CONTROL REGISTER & READ-IN#GATES OKAY.

CONTROL REGISTER/READ-IN GATE TEST
COMPLETE!

PATCHING FOR PRESET COUNTER TEST:

PATCH IOT1 TO COUNTER 1, COUNTER 1'S
S OUTPUT TO J&K INPUTS OF ACFLIP FLOP,
AND THE FLIP FLOP OUTPUT TO CFREE FLAG 0.
PATCH IOT2 TO COUNTER 2, COUNTER 2'S
S OUTPUT TO J&K INPUTS OF ACFLIP FLOP,
AND THE FLIP FLOP OUTPUT TO CFREE FLAG 1.
PATCH IOT4 TO THE RESET INPUTS
OF BOTH FLIP FLOPS.

FLIP FLOPS MUST BE INITIALLY RESET!!

TYPE "GO" WHEN PATCHING COMPLETE.

GO

PRE-SET COUNTER 1 OKAY.
PRE-SET COUNTER 2 OKAY.

PRESET COUNTER TEST COMPLETE!

ADC/MDAC TEST:

PATCH CONTROL REGISTER BIT 0 TO A
NOR GATE, THE NOR OUTPUT OF WHICH
GOES TO EXT. IR AND THE OR OUTPUT
GOES TO EXT. CP.
PATCH CONTROL REGISTER BITS 1-4 EACH
TO A NOR GATE WITH THE COMPLEMENT
OF THE R PULSE. THEN PATCH
NOR GATE #1 TO A/D 1, ETC., SO THAT
THE ADC CONTROL PULSE "R" APPEARS
ONLY WHEN THE CORRESPONDING CONTROL
REGISTER BIT IS A "0".

ANALOG PATCHING:

PATCH EACH MDAC TO AN ADC INPUT AND
TO THE DVM. TYPE MDAC # AND ADC #
OF EACH PAIR TO BE TESTED (ENTER
NOTHING TO TERMINATE TEST).

TEST OPERATION: SET AC SWITCHES 0-10
FOR MDAC READ-IN. WHEN PROGRAM
HALTS, ADC READS INTO AC.
TO CHANGE INPUT, SET AC 0-10 AGAIN
AND DEPRESS "CONTINUE".
TO CHANGE ADC/MDAC PAIR, PUT UP AC 17

MDAC# 3
3
ADC# 1

TYPE "GO" WHEN PATCHING COMPLETE.

G

MDAC# 2
2
ADC# 2

TYPE "GO" WHEN PATCHING COMPLETE.

G

MDAC# 3
4
ADC# 3

TYPE "GO" WHEN PATCHING COMPLETE.

G

MDAC# 8

ALL TESTS COMPLETE!
TYPE GO TO RESTART PROGRAM.

"LOCUTI"
PDP-9/LOCUST HYBRID INTERFACE TEST!

DO YOU WISH PATCHING INSTRUCTIONS?

N

TYPE "NO" AFTER TESTS NOT TO BE RUN.

FREE FLAG/IOT TEST?

CONTROL REGISTER/READ-IN GATE TEST?

PRE-SET COUNTER TEST?

MDAC/ADC TEST?

N

TYPE "GO" WHEN PATCHING COMPLETE.

G

IOT1 OKAY
FREE FLAG 0 BAD
FREE FLAG 1 OKAY
IOT2 BAD
IOT4 OKAY

FREE-FLAG/IOT TEST COMPLETE!

CONTROL REGISTER/READ-IN GATE TEST -
TYPE "GO" WHEN PATCHING COMPLETE.

G

A PROBLEM EXISTS WITH THE FOLLOWING BITS
IN EITHER CONTROL REGISTER OR READ-IN
GATES. AFTER EACH PRINT OUT CHECK THE
LAMP CORRESPONDING TO THAT BIT. IF IT IS
LIT TYPE AN R INDICATING THAT THE READ-
IN GATE IS IN ERROR. IF LAMP NOT LIT
TYPE C INDICATING ERROR IN CONTROL
REGISTER AND POSSIBLE ERROR IN
READ-IN GATE.

ERROR IN BIT 1
TYPE R OR C - R

READ-IN GATE ERROR IN ABOVE BIT.

ERROR IN BIT 3
TYPE R OR C -

C

CONTROL REGISTER ERROR AND POSSIBLY
READ-IN GATE ERROR IN ABOVE BIT.
PATCH A WORKING IOT TO J&K INPUTS OF A
FLIP FLOP AND ITS OUTPUT TO THE ERROR
BIT IN THE READ-IN GATE, THEN TYPE G.

G

CONTROL REGISTER & READ-IN GATE ERROR.

NO FUTHER ERRORS.

CONTROL REGISTER/READ-IN GATE TEST
COMPLETE!

PRESET COUNTER TEST -
TYPE "GO" WHEN PATCHING COMPLETE.

G

PRE-SET COUNTER 1 OKAY.
PRE-SET COUNTER 2 OKAY.

PRESET COUNTER TEST COMPLETE!

ALL TESTS COMPLETE!
TYPE GO TO RERUN PROGRAM.

TYPE CTRL S TO RESTART.

C A FORTRAN MAIN PRORAM WHICH CALLS
C MACRO SUBROUTINES TO TEST THE
C LOCUST/PDP-9 HYBRID INTERFACE.
C COMMUNICATION WITH USER IS VIA
C TELETYPE, BUT LINE LENGTHS
C CONFORM TO CRT EDITING.

C
C WM. R. MOORE JANUARY, 1970
C

```
      INTEGER TESTFO(3), TESTFI(3), ADC
      LOGICAL FI(6), PATCH
      REAL NO
      DATA YES/1HY/, NO/1HN/, GO/1HG/
      PATCH = .TRUE.
      WRITE(5,2222)
2222  FORMAT(1HI,16X,* "LOCUTI"*/2X,
      /* PDP-9/LOCUST HYBRID INTERFACE TE
      #STI*/)
      WRITE(5,1)
1      FORMAT(* DO YOU WISH PATCHING INS
      #TRUCTIONS? *)
      READ(4,2) ANSI
2      FORMAT(A1)
      IF (ANSI.EQ.NO) PATCH = .FALSE.
      WRITE(5,10)
10     FORMAT(/* TYPE "NO" AFTER TESTS N
      NOT TO BE RUN.*/)
      WRITE(5,11)
11     FORMAT(* FREE FLAG/IOT TEST?*)
      READ(4,2) ANS2
      WRITE(5,12)
12     FORMAT(/* CONTROL REGISTER/READ-I
      #N GATE TEST?*)
      READ(4,2) ANS3
      WRITE(5,13)
13     FORMAT(/* PRE-SET COUNTER TEST?*)
      READ(4,2) ANS4
      WRITE(5,14)
14     FORMAT(/* MDAC/ADC TEST?*)
      READ(4,2) ANS5
      IF(ANS2.EQ.NO) GO TO 15
      IF(.NOT.PATCH) GO TO 50
      WRITE(5,100)
100    FORMAT(/* FREE-FLAG/IOT TEST: */
      $1X,* PATCH EACH "PATCHABLE" IOT TO
      $ A 3-INPUT "OR"*/1X,* GATE AND THE
      $ GATE OUTPUT TO J&K INPUTS*/1X,
      $* OF A FLIP FLOP, THEN PATCH THE F
```

```
*FLIP*/1X,* FLOP OUTPUT TO BOTH FREE
* FLAGS. (NOTE */1X,* THAT THE FLIP
* FLOP IS TOGGLED AND MUST*/1X,* BE
* RESET BEFORE STARTING THE TEST.)*
#//)
50  WRITE(5,51)
51  FORMAT(* TYPE "GO" ;WHEN PATCHING
# COMPLETE.*//)
54  READ(4,2) ANSI
      IF (ANSI.EQ.60) GO TO 55
      GO TO 50
55  WRITE(5,56)
56  FORMAT(1H0)
      CALL FFTIOI (TESTFO(1),TESTFO(2),
# TESTFO(3),TESTFI(1),TESTFI(2),
# TESTFI(3))
      DO 3 I=1,3
3   FI(I)=TESTFO(I).EQ.1
      DO 4 J=4,6
      K=J-3
4   FI(J)=TESTFI(K).EQ.1
      IF (FI(1).AND.FI(4)) GO TO 200
      IF (FI(2).AND.FI(5)) GO TO 300
      IF (FI(3).AND.FI(6)) GO TO 400
      IF (FI(1).OR.FI(4)) GO TO 500
      IF (FI(2).OR.FI(5)) GO TO 600
      IF (FI(3).OR.FI(6)) GO TO 700
      WRITE (5,800)
800  FORMAT(* FREE-FLAG/IOT TEST FAILS
#,* / * ONE OF THE FOLLOWING IS TRU
#E;* / * (1) PATCHABLE IOTS ARE INO
#PERATIVE;* / * (2) BOTH FREE-FLAGS
# ARE INOPERATIVE;* / * (3) BOTH (1
#) AND (2).*//)
      GO TO 900
200  WRITE(5,801)
      WRITE(5,802)
      WRITE(5,803)
      IF (FI(1).AND.FI(2)) GO TO 201
      IF (FI(1).AND.FI(3)) GO TO 202
      WRITE(5,814)
204  WRITE(5,815)
      GO TO 900
201  WRITE(5,804)
      IF (FI(1).AND.FI(3)) GO TO 203
      GO TO 204
203  WRITE(5,805)
      GO TO 900
```

```
202      WRITE(5,814)
          WRITE(5,805)
          GO TO 900
300      WRITE(5,801)
          WRITE(5,802)
          WRITE(5,813)
          WRITE(5,804)
          IF (FI(2).AND.FI(3)) GO TO 203
          GO TO 204
400      WRITE(5,801)
          WRITE(5,802)
          WRITE(5,813)
          WRITE(5,814)
          GO TO 203
500      WRITE(5,803)
          IF (FI(1)) GO TO 501
          WRITE(5,811)
          WRITE(5,802)
          IF (FI(4).AND.FI(5)) GO TO 502
          IF (FI(4).AND.FI(6)) GO TO 505
          WRITE(5,814)
          GO TO 204
502      WRITE(5,804)
          IF (FI(1).AND.FI(3)) GO TO 203
          GO TO 204
505      WRITE(5,814)
          GO TO 203
501      WRITE(5,801)
          WRITE(5,812)
          IF (FI(1).AND.FI(2)) GO TO 502
          IF (FI(1).AND.FI(3)) GO TO 505
          WRITE(5,814)
          GO TO 204
600      WRITE(5,813)
          WRITE(5,804)
          IF (FI(2)) GO TO 601
          WRITE(5,811)
          WRITE(5,802)
          IF (FI(5).AND.FI(6)) GO TO 203
          GO TO 204
601      WRITE(5,801)
          WRITE(5,812)
          IF (FI(2).AND.FI(3)) GO TO 203
          GO TO 204
700      WRITE(5,813)
          WRITE(5,814)
          WRITE(5,805)
          IF (FI(3)) GO TO 701
```

```
      WRITE(5,811)
      WRITE(5,802)
      GO TO 900
701      WRITE(5,801)
      WRITE(5,812)
900      WRITE(5,901)
901      FORMAT(* FREE-FLAG/IOT TEST COMP
*#LETE!/*//)
15       IF(ANS3.EQ.NO) GO TO 16
           IF(.NOT.PATCH) GO TO 104
           WRITE(5,101)
161      FORMAT(* CONTROL REGISTER/READ-IN
* GATE TEST*/1X,* PATCH CONTROL RE
*#GISTER OUTPUTS TO*/1X,* CORRESPOND
*#ING READ-IN GATE*/1X,* INPUTS AND
*# TO 6 LOGIC-STATE*/1X,* INDICATOR
*# LAMPS. THE LAMPS ARE*/1X,* USED A
*#S A VISUAL CHECK IN CASE*/1X,* THE
*# READ-IN GATES FAIL.*//)
           GO TO 102
104      WRITE(5,105)
105      FORMAT(* CONTROL REGISTER/READ-IN
* GATE TEST -*)
102      WRITE(5,51)
           READ(4,2) ANSI
           IF(ANS1.EQ.GO) GO TO 103
           GO TO 102
105      WRITE(5,56)
           CALL CONREG
           WRITE(5,125)
125      FORMAT(* CONTROL REGISTER/READ-I
* N GATE TEST*/3X,* COMPLETE!/*//)
16       IF(ANS4.EQ.NO) GO TO 17
           IF(.NOT.PATCH) GO TO 162
           WRITE(5,150)
150      FORMAT(* PATCHING FOR PRESET COUN
*TER TEST*/1X,* PATCH IOT1 TO COUN
*TER 1, COUNTER 1'S */1X,* S OUTPUT
*# TO J&K INPUTS OF A FLIP FLOP,*/1X
*#,* AND THE FLIP FLOP OUTPUT TO FRE
*#E FLAG 0.*/1X,* PATCH IOT2 TO COUN
*TER 2, COUNTER 2'S */1X,* S OUTPUT
*# TO J&K INPUTS OF A FLIP FLOP,*/1X
*#,* AND THE FLIP FLOP OUTPUT TO FRE
*#E FLAG 1.*/1X,* PATCH IOT4 TO THE
*# RESET INPUTS*/1X,* OF BOTH FLIP F
*#LOPS.*/3X,* FLIP FLOPS MUST BE INI
*#TIALY RESET!/*//)
```

```
GO TO 160
162 WRITE(5,163)
163 FORMAT(* PRESET COUNTER TEST -*)
160 WRITE(5,51)
149 READ(4,2) ANSI
150 IF(ANS1.EQ.60) GO TO 161
151 GO TO 160
161 WRITE(5,56)
154 CALL PRECTR
155 WRITE(5,152)
152 FORMAT(* PRESET COUNTER TEST COM
#PLETE!*/)
17 IF(ANS5.EQ.ND) GO TO 1111
17 IF(.NOT.PATCHD) GO TO 186
175 WRITE(5,176)
176 FORMAT(* ADC/MDAC TEST:*/1X,* PAT
#CH CONTROL REGISTER BIT 0 TO A*/1X
*,* NOR GATE, THE NOR OUTPUT OF WMI
#CHA*/1X,* GOES TO EXT. IR AND THE 0
#R OUTPUT*/1X,* GOES TO EXT. CP.*/1
#X,* PATCH CONTROL REGISTER BITS 1-
#4 EACH*/1X,* TO A NOR GATE WITH IN
#E COMPLEMENT*/1X,* OF THE R PULSE.
# THEN PATCH*/1X,* NOR GATE #1 TO A
#/D 1, ETC., SO THAT*/1X,* THE ADC
# CONTROL PULSE "R" APPEARS*/1X,* 0
# ONLY WHEN THE CORRESPONDING CONTROL
#*/1X,* REGISTER BIT IS A "0". */
#* ANALOG PATCHING:*/1X,
0* PATCH EACH MDAC TO AN ADC INPUT
# AND*/1X,* TO THE DVM. TYPE MDAC #
# AND ADC #*/1X,* OF EACH PAIR TO 0
# TESTED (ENTER*/1X,* NOTHING TO T
# ERMINATE TEST).*/
185 GO TO 185
186 WRITE(5,184)
184 FORMAT(* MDAC/ADC -*)
183 WRITE(5,183)
183 FORMAT(* TEST OPERATION: *,
#* SET AC SWITCHES 0-10*/1X,* FOR M
#DAC READ-IN. WHEN PROGRAM*/1X,* HA
#LTS, ADC READS INTO AC.*/1X,* TO C
#HANGE INPUT, SET AC 0-10 AGAIN*/1X
#,* AND DEPRESS "CONTINUE."*/1X,* T
#O CHANGE ADC/MDAC PAIR, PUT UP AC
# 17*/1X,* ONLY, THEN DEPRESS CONTI
#UE.*//)
177 WRITE(5,178)
```

```
178 FORMAT(* MDAC# :*)  
READ(4,179) MDAC  
IF(MDAC.EQ.0) GO TO 1111  
179 FORMAT(II)  
WRITE(5,180)  
180 FORMAT(* ADC# :*)  
READ(4,179) ADC  
182 WRITE(5,56)  
WRITE(5,51)  
READ(4,2) ANSI  
IF(ANSI.EQ.60) GO TO 181  
GO TO 182  
181 WRITE(5,56)  
CALL CONV (MDAC,ADC)  
GO TO 177  
1111 WRITE(5,1112)  
1112 FORMAT(* ALL TESTS COMPLETE!/*/* T  
*YPE GO TO RESTART PROGRAM.*//)  
GO TO 54
```

C FORMAT STATEMENTS FOR
C FREE-FLAG/IOT TEST.

```
801 FORMAT(* FREE FLAG 0 OKAY*)  
802 FORMAT(* FREE FLAG 1 OKAY*)  
803 FORMAT(* IOT1 OKAY*)  
804 FORMAT(* IOT2 OKAY*)  
805 FORMAT(* IOT4 OKAY*)  
811 FORMAT(* FREE FLAG 0 BAD*)  
812 FORMAT(* FREE FLAG 1 BAD*)  
813 FORMAT(* IOT1 BAD*)  
814 FORMAT(* IOT2 BAD*)  
815 FORMAT(* IOT4 BAD*)  
END
```

/MACRO SUBROUTINE FOR LOCUT1 TO TEST
/FREE FLAGS AND PATCHABLE IOTS.

.TITLE FFIOT
.GLOBL FFIOT,.DA
FFIOT 0 /ENTRY POINT.
JMS* .DA /LINK WITH LOCUT1.
JMP .+7 /JUMP ARGUMENT LIST.
TESTFG 0 /F01 (IN F(XY)), X DENOTES
0 /F02 (THE FLAG BEING TESTED,
0 /F04 (Y DENOTES THE IOT USED
TESTFI 0 /F11 (TO TEST IT.)
0 /F12
0 /F14

/
LAC (DAC# TESTF0) /INITIALIZE
DAC INCI /INCI.
LAC (-S /INITIALIZE
DAC INCRI /INCRI.
INCRI 0 /LOOP INDEX.
INC1 0 /INITIALIZATION OF
INC1 0 /THE PRECEEDING
ISZ INCI /ARGUMENTS TO I.
ISZ INCRI /THIS ALLOWS ASSUMP-
JMP INC1 /TION OF A PROPERLY
/WORKING COMPONENT,
/UNLESS PROVEN
/OTHERWISE.

/INITIALIZE TEST INSTRUCTIONS.

LAC (701621
DAC IOTFF0
DAC TOG
LAC (DZMK TESTF0)
DAC IOTFFA
LAC (DZM# TESTFI)
DAC IOTFFB

/TEST BOTH FREE FLAGS (FF0 & FF1) WITH
/ALL THREE PATCHABLE IOTS.

/
703444 /CLEAR FF0.
703544 /CLEAR FF1.
IOTFF0 0 /ISSUE IOT.
701541 /SKIP ON FF0 SET.
IOTFFA 0 /B IF FF0 NOT SET.
ISZ IOTFFA /SET UP FOR NEXT IOT.
701521 /SKIP ON FF1 SET.

```
IOTFFB 0      /0 IF FFI NOT SET.  
TOG  0      /TOGGLE FLIP-FLOP.  
LAC IOTFF0  /TEST FOR  
SAD (701624 /LAST IOT.  
JMP .+7  
ISZ IOTFFB /SET UP FOR NEXT IOT.  
AND (7      /CHANGE THE IOT THAT  
ADD IOTFF0 /IS ISSUED TO  
DAC IOTFF0 /701622, AND THEN  
DAC TOG   /TO 701624.  
JMP IOTFF0  
JMP* FFIOT  
.END
```

/MACRO SUBROUTINE CALLED BY LOCUTI TO
/TEST THE CONTROL REGISTER AND READ-IN
/GATES. USES MACRO-9 I/O.

/

- .TITLE CONREG
- .NOGEN /SUPPRESS MACRO GENERATION
- .GLOBL CONREG
- .IODEV 4,5

CONREG 0 /ENTRY POINT.

- .INIT 4,0,CONREG /INPUT.
- .INIT 5,1,CONREG /OUTPUT.

LAC <770000

701647 /CLEAR, LOAD & TRANSFER ALL
/I'S TO CONTROL REGISTER.

702212 /TRANSFER READ-IN GATES,
/WHICH ARE PATCHED TO
/CONTROL REGISTER, BACK
/TO PDP-9.

AND <770000 /MASK LAST 12 BITS.

SAD <770000 /TEST THE RESULT.

JMP T1 /IF I'S TRANSFERED OK,
/CHECK WITH ALL 0'S.

DAC RES /SAVE TEST RESULT.

JMP T2 /IF I'S DON'T TRANSFER,
/CHECK THE BITS MANUALLY.

T1 LAC <0

701647 /CLEAR, LOAD & TRANSFER ALL
/0'S TO CONT. REG.

702212 /TRANSFER READ-IN GATES.

AND <770000

SNA /TEST THE RESULT.

JMP ALLOK /IF BOTH 0'S AND I'S
/TRANSFER OK, TEST COM-
/PLETE.

CMA /SET ERROR BITS TO 0.

DAC RES /SAVE TEST RESULT.

LAC <770000 /RELOAD CONTROL.

701647 /REGISTER WITH I'S.

T2

- .WRITE 5,2,NOTEPE,NOTEPEV
- .WAIT 5
- .WRITE 5,2,CONT1,CONT1V
- .WAIT 5
- .WRITE 5,2,CONT2,CONT2V
- .WAIT 5
- .WRITE 5,2,CONT3,CONT3V
- .WAIT 5
- .WRITE 5,2,CONT4,CONT4V

```
.WAIT 5
.WRITE 5,2,CONT5,CONT5V
.WAIT 5
.WRITE 5,2,CONT6,CONT6V
.WAIT 5
.WRITE 5,2,CONT7,CONT7V
.WAIT 5
.WRITE 5,2,CONT8,CONT8V
.WAIT 5
.WRITE 5,2,CARR,CARRV
.WAIT 5
/
/*DEFINE MACROS TO TEST BITS MANUALLY.
/
.DEFIN BIT,LIT,NOTEA,NOTEAV
.ETC A,B,C,NEXT
LAC RES
AND LIT /MASK ALL BUT ERROR BIT.
SZA
JMP NEXT /JMP OUT OF MACRO.
.WRITE 5,2,NOTEA,NOTEAV
.WAIT 5
.WRITE 5,2,NOTEX,NOTEJV
.WAIT 5
.READ 4,2,INBUF,4
.WAIT 4
.WRITE 5,2,CARR,CARRV /CARRIAGE
.WAIT 5
/LAC INBUF+2
AND C774000 /MASK LAST 11 BITS.
SAD C414000 /ASCII C.
JMP A /READ-IN GATE TEST.
.WRITE 5,2,NOTER,NOTERV
.WAIT 5
.WRITE 5,2,CARR,CARRV
.WAIT 5
JMP NEXT /JUMP OUT OF MACRO.
A .WRITE 5,2,NOTECE,NOTEJV
.WAIT 5
.WRITE 5,2,NOTER,NOTERV
.WAIT 5
B .WRITE 5,2,NOTED,NOTEDV
.WAIT 5
.WRITE 5,2,CONTA,CONTAV
.WAIT 5
.WRITE 5,2,CONTB,CONTBV
.WAIT 5
.READ 4,2,INBUF,4
```

```
.WAIT 4
.WRITE 5,2,CARR,CARRV
.WAIT 5
LAC INBUF+2
AND C774000 /MASK
SAD C434000 /ASCII "G.
JMP .+2
JMP B /WRITE NOTED.
701627 /ISSUE FREE IOTS.
702212 /READ-IN GATE TRANSFER.
701627 /TOGGLE FLIP FLOP.
AND LIT /MASK ALL BUT ERROR BIT.
SNA
JMP C /READ-IN ERROR.
.WRITE 5,2,NOTEV,NOTEV
.WAIT 5
.WRITE 5,2,CARR,CARRV
.WAIT 5
JMP NEXT /JMP OUT OF MACRO.
C .WRITE 5,2,NOTEV,NOTEV
.WAIT 5
.WRITE 5,2,CARR,CARRV
.WAIT 5
.ENDM
/
/*CALL BIT MACRO TO TEST EACH BIT AND
/OUTPUT ERROR MESSAGES.
/
    .GEN /GENERATE MACROS.
    BIT C40000,NOTE0,NOTE0V,A1,B1,$
C1,NEXT1
    .NOGEN /SUPPRESS MACRO GENERATION
NEXT1  BIT C20000,NOTE1,NOTE1V,A2,B2,$
C2,NEXT2
NEXT2  BIT C10000,NOTE2,NOTE2V,A3,B3,$
C3,NEXT3
NEXT3  BIT C40000,NOTE3,NOTE3V,A4,B4,$
C4,NEXT4
NEXT4  BIT C20000,NOTE4,NOTE4V,A5,B5,$
C5,NEXT5
NEXT5  BIT C10000,NOTE5,NOTE5V,A6,B6,$
C6,NEXT6
NEXT6  .WRITE 5,2,CARR,CARRV
    .WAIT 5
    .WRITE 5,2,NOTEV,NOTEV
    .WAIT 5
    JMP* CONREG
ALLOC  .WRITE 5,2,OK,OKV
```

.WAIT 5
.WRITE 5,2,CARR,CARRY
.WAIT 5
JMP* CONREG

/I/O REGISTERS.

RES 0 /TEST RESULT.
INBUF .BLOCK 4 /INPUT BUFFER.
OK OKV/2*1000+502; 0 /HEADER,
.ASCII /CONTROL REGISTER & RE/
.ASCII /AD-IN GATES OKAY./<15>
OK V=. -OK
NOTEV NOTEPV/2*1000+502; 0 /HEADER
.ASCII /A PROBLEM EXISTS WITH TH/
.ASCII /E FOLLOWING BITS/<15>
NOTEPV=. -NOTEV
CONT1 CONT1 V/2*10000+502; 0 /HEADER
.ASCII /IN EITHER CONTROL REGIST/
.ASCII /ER OR READ-IN/<15>
CONT1 V=. -CONT1
CONT2 CONT2 V/2*1000+502; 0 /HEADER
.ASCII /GATES. AFTER EACH PRINT /
.ASCII /OUT CHECK THE/<15>
CONT2 V=. -CONT2
CONT3 CONT3 V/2*1000+502; 0 /HEADER
.ASCII /LAMP CORRESPONDING TO TH/
.ASCII /AT BIT. IF IT IS/<15>
CONT3 V=. -CONT3
CONT4 CONT4 V/2*1000+502; 0 /HEADER
.ASCII /LIT TYPE AN R INDICATING/
.ASCII / THAT THE READ-/<15>
CONT4 V=. -CONT4
CONT5 CONT5 V/2*1000+502; 0 /HEADER
.ASCII /IN GATE IS IN ERROR. IF /
.ASCII /LAMP NOT LIT/<15>
CONT5 V=. -CONT5
CONT6 CONT6 V/2*1000+502; 0 /HEADER
.ASCII /TYPE C INDICATING ERROR /
.ASCII /IN CONTROL/<15>
CONT6 V=. -CONT6
CONT7 CONT7 V/2*1000+502; 0 /HEADER
.ASCII /REGISTER AND POSSIBLE ER/
.ASCII /ROR IN/<15>
CONT7 V=. -CONT7
CONT8 CONT8 V/2*1000+502; 0 /HEADER
.ASCII /REAL-IN GATE./<15>
CONT8 V=. -CONT8

NOTE0 NOTE0 V/2*1000+502; 0 /HEADER
.ASCII /ERROR IN BIT 0/<15>
NOTE0 V=.-NOTE0
NOTEI NOTEI V/2*1000+502; 0 /HEADER
.ASCII /ERROR IN BIT 1/<15>
NOTEI V=.-NOTEI
NOTE2 NOTE2 V/2*1000+502; 0 /HEADER
.ASCII /ERROR IN BIT 2/<15>
NOTE2 V=.-NOTE2
NOTES NOTES V/2*1000+502; 0 /HEADER
.ASCII /ERROR IN BIT 3/<15>
NOTES V=.-NOTES
NOTE4 NOTE4 V/2*1000+502; 0 /HEADER
.ASCII /ERROR IN BIT 4/<15>
NOTE4 V=.-NOTE4
NOTES NOTES V/2*1000+502; 0 /HEADER
.ASCII /ERROR IN BIT 5/<15>
NOTE5 V=.-NOTES
NOTEX NOTEX V/2*1000+502; 0 /HEADER
.ASCII /TYPE R OR C - /<175>
NOTEX V=.-NOTEX
CARR CARR V/2*1000+502; 0 /HEADER
.ASCII <15>
CARR V=.-CARR
NOTER NOTER V/2*1000+502; 0 /HEADER
.ASCII /READ-IN GATE ERROR IN AB/
.ASCII /OVE BIT./<15>
NOTER V=.-NOTER
NOTE C NOTE C V/2*1000+502; 0 /HEADER
.ASCII /CONTROL REGISTER ERROR A/
.ASCII /ND POSSIBLY/<15>
NOTE CV=.-NOTE C
NOTED NOTED V/2*1000+502; 0 /HEADER
.ASCII /PATCH A WORKING IOT TO J/
.ASCII /&K INPUTS OF A/<15>
NOTED V=.-NOTED
CONTA CONTA V/2*1000+502; 0 /HEADER
.ASCII /FLIP FLOP AND ITS OUTPUT/
.ASCII / TO THE ERROR/<15>
CONTA V=.-CONTA
CONTB CONTB V/2*1000+502; 0 /HEADER
.ASCII /BIT IN THE READ-IN GATE,/ /
.ASCII / THEN TYPE G./<15>
CONTB V=.-CONTB
NOTE E NOTE E V/2*1000+502; 0 /HEADER
.ASCII /CONTROL REGISTER ERROR /
.ASCII /ONLY./<15>
NOTE EV=.-NOTE E

NOTEF NOTEFV/2*1000+502; 0 /HEADER
.ASCII /CONTROL REGISTER & READ-/
.ASCII /IN GATE ERROR./<15>

NOTEFV=-NOTEF

NOTEG NOTEGV/2*1000+502; 0 /HEADER
.ASCII /NO FUTHER ERRORS./<15>

NOTEGV=-NOTEG

.END

.TITLE PRECTR /MACRO SUBROUTINE
/CALLED BY LOCUTI TO
/TEST PRESET COUNTERS.

.GLOBL PRECTR,ERROR

.IODEV 5

PRECIR 0 /ENTRY POINT.

.INIT 5,1

LAC C0 /CLEAR CONTROL REG. FOR
701647 /MDAC/ADC TEST; NEXT.

LAC C-1130 /DECIMAL 690.

DAC INCR

LAC C1127 /DECIMAL 599.

ALS 10 /YIELDS 1127 IN AC B-9.

CMA

701546 /CLEAR & LOAD CTR1.

IIOTA 701621 /ISSUE IOT1.

NOP

NOP

701541 /SKIP ON FREE FLAG 0.

JMP .+2

JMP OUT1

ISZ INCR

JMP IIOTA

JMP SETI /CTR FAILS TO SET ON
/600 PULSES.

OUT1 701624 /RESET FLIP FLOP WITH IOT4

LAC INCR /INCR HASN'T BEEN
TAD C1 /INCREMENTED ON LAST
/COUNT.

DAC ERRI

SZA

JMP CTR1 /CTR1 COUNTS WRONG.

.WRITE 5,2,NOTEA,NOTEAV /CTR1 OK.

.WAIT 5

BC2 LAC C-1130 /BEGIN CTR2 TEST.

DAC INCR

LAC C1127

ALS 10

CMA

701526

IIOTB 701622 /ISSUE IOT2.

NOP

NOP

701521 /SKIP ON FREE FLAG 1.

JMP .+2

JMP OUT2

ISZ INCR

JMP IIOTB

JMP SET2
OUT2 701624 /RESET FLIP FLOP WITH IOT4
LAC INCR
TAD (1
DAC ERR2
SZA
JMP CTR2
.WRITE 5,2,NOTEB,NOTEBV /CTR2 OK.
.WAIT 5
JMP# PRECTR
CTRI JMS* ERROR
JMP .+3
PCI
ERR1#
JMP BC2
SET1 .WRITE 5,2,NOTE2,NOTE2 V
.WAIT 5
JMP BC2
CTR2 JMS* ERROR
JMP .+3
PC2
ERR2#
JMP# PRECTR
SET2 .WRITE 5,2,NOTE4,NOTE4 V
.WAIT 5
JMP# PRECTR
PCI 1
PC2 2
NOTEA NOTEAV/2*1000+502; 0
.ASCII /PRE-SET COUNTER 1 /
.ASCII /OKAY./<15>
NOTEAV=.~NOTEA
NOTEB NOTEBV/2*1000+502; 0
.ASCII /PRE-SET COUNTER 2 /
.ASCII /OKAY./<15>
NOTEBV=.~NOTEB
NOTE2 NOTE2 V/2*1000+502; 0
.ASCII /COUNTER 1 FAILS TO SET/
.ASCII / AFTER 600 PULSES./<15>
NOTE2 V=.~NOTE2
NOTE4 NOTE4 V/2*1000+502; 0
.ASCII /COUNTER 2 FAILS TO SET/
.ASCII / AFTER 600 PULSES./<15>
NOTE4 V=.~NOTE4
.END

ERROR

PAGE 1

```
SUBROUTINE ERROR (ICTR,IERR)
C OUTPUT FOR PRECTR OF LOCUT1.
C NOTE: IERR IS NEGATIVE.
      ICOUNT = 600 + IERR
      WRITE(5,1) ICTR,ICOUNT
1      FORMAT(* COUNTER *,I1,* SETS AFTE
      #R COUNTING TO *,I3,*.*)
      RETURN
      END
```

```
.TITLE CONV      /SUBROUTINE CALLED
.GLOBL CONV,.DA /BY LOCUTI TO
CONV    0          ' /TEST MDAC'S
        JMS* .DA      /AND ADC'S.
        JMP .+3
MDAC    0
ADC     0
/
/CLEAR CONTROL REGISTER.
LAC (0
701647
/
/CHOOSE ADC AND MDAC.
/
CKDAC  LAC# MDAC
SAD (1
JMP M1
SAD (2
JMP M2
SAD (3
JMP M3
SAD (4
JMP M4
JMP* CONV
CKADC  LAC# ADC
SAD (1
JMP A1
SAD (2
JMP A2
SAD (3
JMP A3
SAD (4
JMP M4
JMP* CONV
/
/THE VARIABLE REG WILL BE USED WITH THE
/CONTROL REGISTER TO PUT LOCUST IN RESET
/AND COMPUTE (USING BIT 0) AND TO CON-
/TROL THE COMMAND SIGNALS FOR THE ADC'S.
/CONTROL REG. BITS 1-4 ARE PATCHED TO
/NOR GATES ALONG WTH THE COMPLEMENT OF
/THE R PULSE. THE GATE OUTPUT PROVIDES
/THE COMMAND FOR THE ADC'S WHEN THE COR-
/RESPONDING CONTROL REG. BIT IS 0.
/
/TEST THE ADC'S AND MDAC'S IN PAIRS AS
/DESIGNATED BY LOCUTI GFROM TTY INPUT.
/
```

I LAS.
J1 0 /CLEAR, LOAD, AND TRANSFER
/TO MDAC.
LAC REG
701647
SKI 0 /SKIP ON ADC FLAG.
JMP .-1
R1 0 /READ ADC.
AND C777600 /MASK OFF UNUSED
/BITS.
HLT
LAC C360000 /PUT LOCUST IN RESET.
701647
LAS
SAD C1
JMP* CONV
JMP CONT

INITIALIZATION OF INSTRUCTIONS.

LAC C703427
DAC MDAC1
JMP CKADC
LAC C703527
DAC MDAC1
JMP CKADC
LAC C703627
DAC MDAC1
JMP CKADC
LAC C703727
DAC MDAC1
JMP CKADC
LAC C703441
DAC ADCSKI
LAC C703452
DAC ADCRI
LAC C560000
DAC REG#
JMP CONT
LAC C703541
DAC ADCSKI
LAC C703552
DAC ADCRI
LAC C660000
DAC REG
JMP CONT
LAC C703641
DAC ADCSKI

CONV

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LAC (703652
DAC ADCR1
LAC (720000
DAC REG
JMP CONT
LAC (703741
DAC ADCSK1
LAC (703652
DAC ADCR1
LAC (740000
DAC REG
JMP CONT
.END